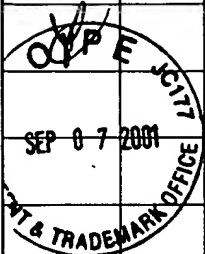


FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. <b>169.1644</b>		APPLICATION NO. <b>09/805,877</b>	
APPLICANT <div style="text-align: center; font-weight: bold; font-size: 1.2em;">DOMINIC YIP</div>						
FILING DATE <div style="text-align: center; font-weight: bold;">March 15, 2001</div>					GROUP <div style="text-align: center; font-weight: bold;">2621</div>	



  

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	6,266,450B1	7/01	Yip et al.	832	240		
<div style="border: 1px solid black; padding: 5px; transform: rotate(-5deg); display: inline-block;">             RECEIVED              SEP 10 2001              Technology Center 2600           </div>							

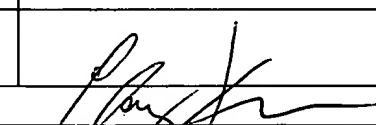
  

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
		E. Stollnitz, Wavelets For Computer Graphics, Theory and Applications, p.5
		A. Bruce, Wavelet Analysis, IEEE Spectrum, Vol. 33, No. 10 (1996), pp. 26-35.

EXAMINER 	DATE CONSIDERED <div style="font-size: 1.5em; font-family: cursive;">6/22/04</div>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.